# MSKSEMI















**ESD** 

TVS

TSS

MOV

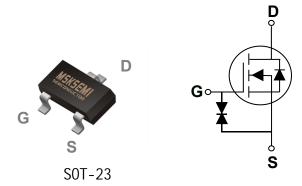
**GDT** 

**PLED** 

# Brodnet data speet

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BVDSS	RDSON	ID
55V	1.2R	0.3A

#### **Features**

- 55V,0.3A, RDS(ON) =1.2Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

### **Applications**

- Motor Drive
- Power Tools
- LED Lighting

# Absolute Maximum Ratings T Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>D</sub> S	Drain-Source Voltage	55	V
Vgs	Gate-Source Voltage	±20	V
L	Drain Current – Continuous (T₄=25°C)	0.3	А
lD .	Drain Current – Continuous (T₄=70°C)	0.16	Α
Ірм	Drain Current – Pulsed <sup>1</sup>	0.8	Α
D-	Power Dissipation (T₄=25°C)	0.35	W
PD	Power Dissipation – Derate above 25°C	0.003	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		357	°C/W





### Electrical Characteristics (T<sub>J</sub>=25 $^{\circ}$ C , unless otherwise noted)

#### Off Characteristics

Syml	ool	Parameter Conditions		Min.	Тур.	Max.	Unit
BV₀	SS	Drain-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =250uA		55			V
1	_	Drain Source Leakage Current	V <sub>DS</sub> =55V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
IDS	S	Drain-Source Leakage Current	V <sub>DS</sub> =40V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			100	uA
lgs	s	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±10	uA

#### On Characteristics

Process	Ctatia Dunin Course On Bosistanas	Vgs=10V , ID=0.2A		1.2	1.5	Ω
RDS(ON)	Static Drain-Source On-Resistance	Vgs=4.5V , Ip=0.1A		1.5	2.5	Ω
V <sub>G</sub> S(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	8.0	1.1	1.5	V
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =0.2A		0.5		S

### Dynamic and switching Characteristics

Qg	Total Gate Charge <sup>2, 3</sup>			3.7	
Qgs	Gate-Source Charge <sup>2 , 3</sup> V <sub>DS</sub> =30V , V <sub>GS</sub> =10V , I <sub>D</sub> =0.2A		-	0.9	 nC
Qgd	Gate-Drain Charge <sup>2, 3</sup>			0.4	
Td(on)	Turn-On Delay Time <sup>2,3</sup>			3	
Tr	Rise Time <sup>2,3</sup> $V_{DD}$ =30V , Vgs=10V , Rg=6 $\Omega$			5	 
Td(off)	Turn-Off Delay Time <sup>2,3</sup>	In=0.2A		14	 ns
Tf	Fall Time <sup>2,3</sup>			9	
Ciss	Input Capacitance			25.5	
Coss	Output Capacitance Vps=30V , Vgs=0V , F=1MHz			17	 pF
Crss	Reverse Transfer Capacitance			7.8	

#### Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	\/\/\/\/			0.3	Α
lsм	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			0.6	Α
Vsp	Diode Forward Voltage	ltage V <sub>GS</sub> =0V , Is=0.2A , T <sub>J</sub> =25℃			1.4	V
trr	Reverse Recovery Time	rse Recovery Time V <sub>R</sub> =50V, Is=0.2A		3.4		ns
Qrr	Reverse Recovery Charge	_  dl/dt=100A/µs, Tյ=25°C		0.7		nC

- Note:
  1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
   Essentially independent of operating temperature.

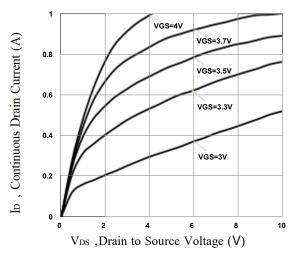


Fig. 1 Typical Output Characteristics

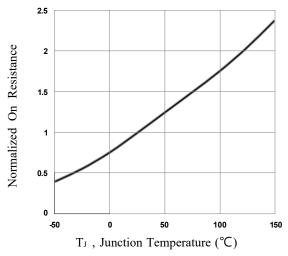


Fig. 3 Normalized RDSON vs.  $T_{\rm J}$ 

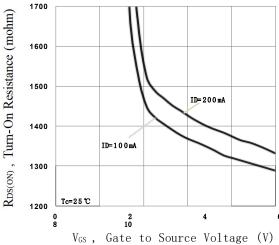


Fig. 5 Turn-On Resistance vs. V<sub>GS</sub>

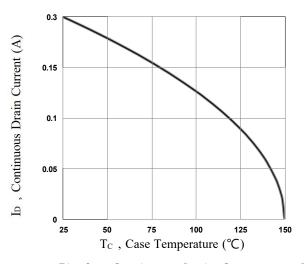


Fig. 2 Continuous Drain Current vs. Tc

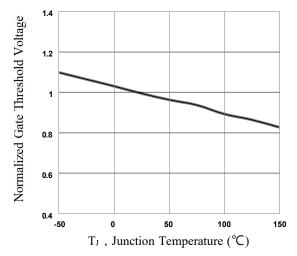


Fig. 4 Normalized V<sub>th</sub> vs. T<sub>J</sub>

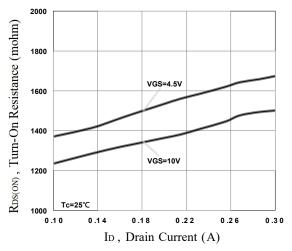


Fig. 6 Turn-On Resistance vs. ID



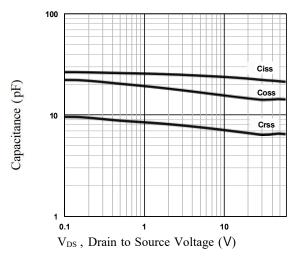
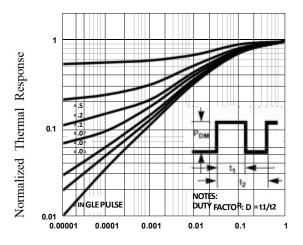


Fig. **7** Capacitance Characteristics



Square Wave Pulse Duration (s)

Normalized Transient

Fig. 9

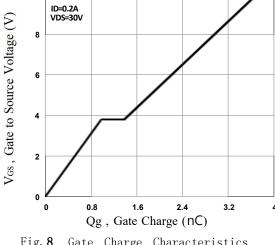
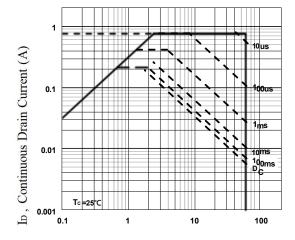


Fig. 8 Gate Charge Characteristics



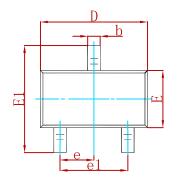
V<sub>DS</sub>, Drain to Source Voltage (V)

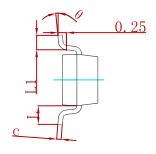
Fig. 10 Maximum Safe Operation Area

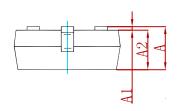


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#### PACKAGE MECHANICAL DATA

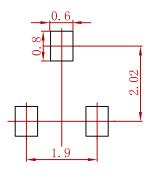






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950	) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
BSS138NH6327-MS	SOT-23	3000

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